

**Notice of References Cited**

Application/Control No.

10/501,383

Applicant(s)/Patent Under  
Reexamination  
KANEGAE ET AL.

Examiner

HENOK G. HEYI

Art Unit

2627

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0177914 A1	11-2002	Chase, Tim	700/94
*	B	US-2002/0164152 A1	11-2002	Kato et al.	386/95
*	C	US-6,839,059 B1	01-2005	Anderson et al.	345/501
*	D	US-6,985,411 B2	01-2006	Kanegae et al.	369/30,04
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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